Notice of References Cited

Application/Control No. 09/883,199	Reexamination	Applicant(s)/Patent Under Reexamination SHINGAI ET AL.		
Examiner	Art Unit			
Jorge L. Ortiz-Criado	2655	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,319,582	11-2001	Tominaga et al.	369/283
	В	US-6,348,251	02-2002	Tsai et al.	428/64.4
	С	US-6,358,589	03-2002	Tsai et al.	428/64.4
	D	US-6,515,952	02-2003	Kikukawa et al.	369/59.12
	Ε	US-			
	F	US-			
	G	US-		,	
	Н	US-			
	1	US-			
	J	US-			
	κ	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
ſ	Z	EP 871164 A2	10-1998	European Patent	KATO et al.	G11B 07/24
ſ	0	JP 11073692 A	03-1999	Japan	TAKAHASHI et al.	G11B 07/26
,	٩	JP 09007176 A	01-1997	Japan	TAKADA et al.	G11B 07/00
i	ď	EP 1011099 A1	06-2000	European Patent	KIKUKAWA et al.	G11B 07/013
į	R	JP 11110817 A	04-1999	Japan	TOMINAGA et al.	G11B 07/24
	s	JP 11096554 A	04-1999	Japan	TOMINAGA et al.	G11B 07/00
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hosaka et al., Nanometer-Sized Phase-Change recording Using a Scanning Near-Field Optical Microscope with a Laser Diode, January 1996, Jpn. J. Appl. Phys. Vol. 35 pp. 443-447.
	v	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.